

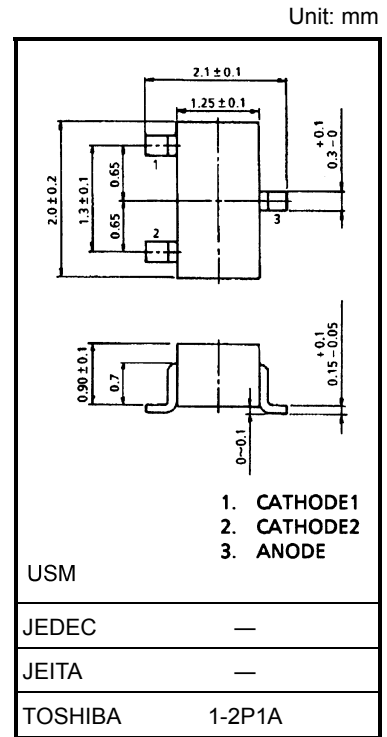
DF3A8.2LFU

Diodes for Protecting against ESD

- The mounting of two devices on an ultra-compact package allows the number of parts and the mounting cost to be reduced.
- The zener voltage corresponds to the E24 Series.
- Low Terminal capacitance (between Cathode and Anode)
: $C_T = 5.0 \text{ pF}$ (typ.)

Maximum Ratings (Ta = 25°C)

| Characteristics | Symbol | Rating | Unit |
|---------------------------|-----------|-----------|------|
| Power dissipation | P | 100 | mW |
| Junction temperature | T_j | 125 | °C |
| Storage temperature range | T_{stg} | -55 ~ 125 | °C |



Electrical Characteristics (Ta = 25°C)

Weight: 0.006 g (typ.)

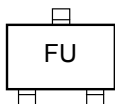
| Characteristics | Symbol | Test Condition | Min | Typ. | Max | Unit |
|---|----------|--|-----|------|-----|---------------|
| Zener voltage | V_Z | $I_Z = 5 \text{ mA}$ | 7.8 | 8.2 | 8.6 | V |
| Dynamic impedance | Z_Z | $I_Z = 5 \text{ mA}$ | — | — | 60 | Ω |
| Knee dynamic impedance | Z_{ZK} | $I_Z = 0.5 \text{ mA}$ | — | — | 100 | Ω |
| Reverse current | I_R | $V_R = 5 \text{ V}$ | — | — | 0.5 | μA |
| Terminal capacitance (between Cathode and Anode) | C_T | $V_R = 0 \text{ V}, f = 1 \text{ MHz}$ | — | 5.0 | — | pF |

Guaranteed Level of ESD Immunity

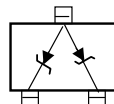
| Test Condition | ESD Immunity Level |
|-------------------------------------|--------------------|
| IEC61000-4-2 (Contact discharge) | $\pm 6 \text{ kV}$ |

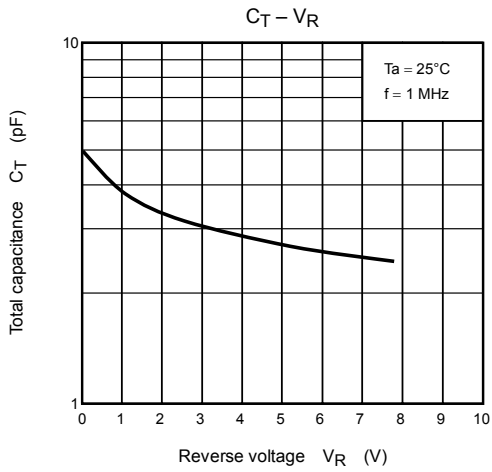
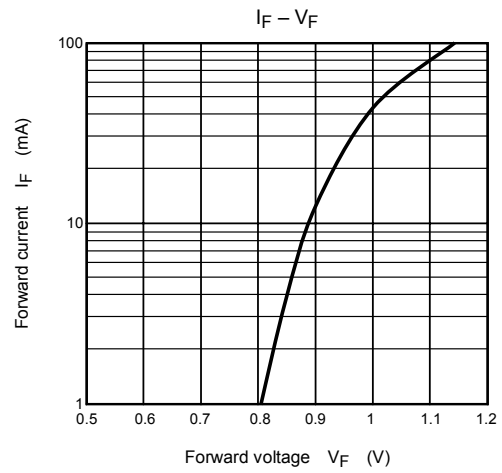
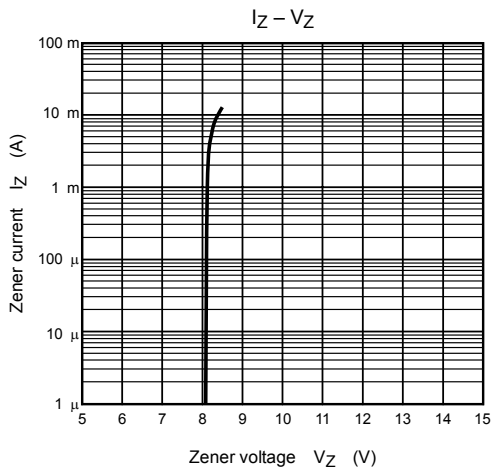
Criterion: No damage to device elements

Marking



Equivalent Circuit (top view)





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